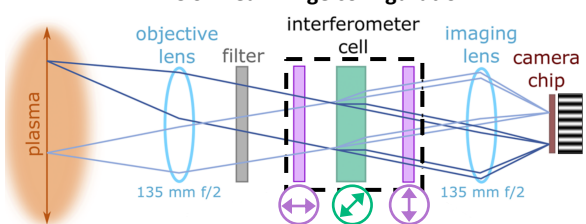


Coherence imaging spectroscopy

Coherence imaging spectroscopy (CIS) is an optical technique that uses a polarization interferometer to obtain 2D images of plasma parameters

Compared to dispersive spectroscopy, CIS has higher optical throughput and gives more spatial information, at the cost of reduced spectral information

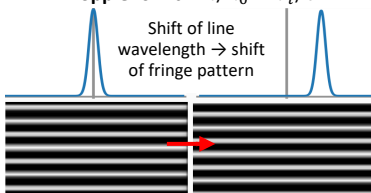
CIS linear fringe configuration



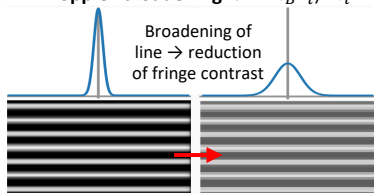
Filter isolates light from a single spectral line
First polarizer linearly polarizes input light
Birefringent crystal imparts a wavelength-dependent phase delay
Second polarizer acts as an analyzer, converting the phase delay into an intensity modulation

Spectroscopic information is encoded into a fringe pattern having a linear spatial carrier (straight fringes)

Doppler shift: $\Delta\lambda/\lambda_0 = v_i/c$



Doppler broadening: $\sigma = k_B T_i / m_i$

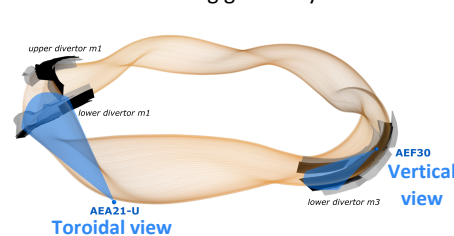


CIS diagnostic on W7-X

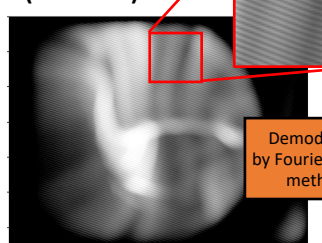
Two CIS diagnostics on W7-X, viewing plasma toroidally and vertically [V. Perseo et al, RSI 91 013501 (2020)]:

- ~1 cm spatial resolution
- ~50 ms time resolution
- Calibrated before/after every discharge using a tunable laser

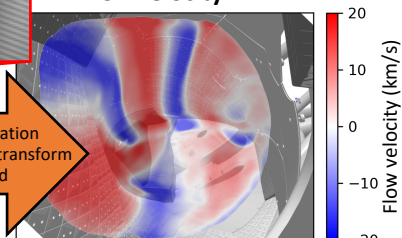
CIS viewing geometry



Interference pattern (raw data)



C²⁺ velocity

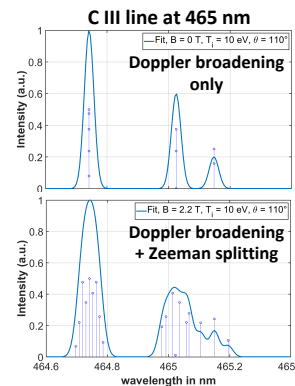


Demodulation by Fourier transform method

Accounting for Zeeman splitting in T_i analysis

Major challenge measuring scrape-off layer (SOL) T_i on W7-X: Zeeman splitting and Doppler broadening have comparable effect on linewidth

- SOL T_i in range of 10's of eV
- Magnetic field varies 2.2–2.9 T throughout plasma
- Measuring T_i requires Zeeman splitting to be modelled or independently measured



CIS contrast given by $\zeta = \zeta_I \zeta_D \zeta_{MZ} \zeta_B$

- ζ_I : instrument contrast (calibration factor)
- ζ_D : Doppler contrast, $\zeta_D = \exp[-T_i/T_C]$
- ζ_{MZ} : Contrast due to line splitting (multiplet and Zeeman effects)
- ζ_B : Contrast due to background light (e.g. bremsstrahlung or divertor thermal emission)

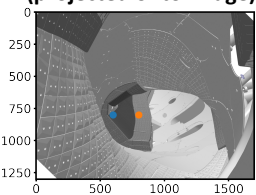
Zeeman contrast calculated along every CIS line of sight (LOS)

- Magnetic field B is generated by coils \rightarrow known with high accuracy throughout plasma
- Zeeman splitting calculated along CIS lines of sight \rightarrow gives ζ_{MZ} along lines of sight

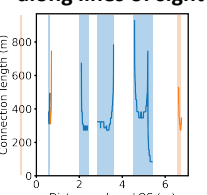
$$\zeta_{MZ} = \left| \sum_m \sum_z I_{m,z} e^{2\pi i \tilde{N} (v_{m,z} - v_0)} \right|$$

$I_{m,z}$: intensity of multiplet/Zeeman component
 $v_{m,z}$: frequency of multiplet/Zeeman component
 v_0 : line center frequency
 \tilde{N} : interferometer group delay

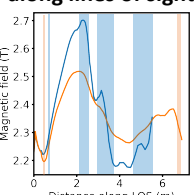
Example CIS lines of sight (projected onto image)



Connection length along lines of sight



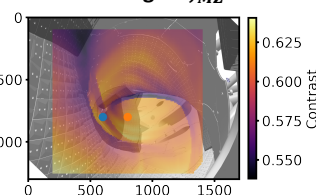
Magnetic field along lines of sight



Connection length used to determine emitting volume:

- L_C is infinite \rightarrow confined plasma \rightarrow no emission
- L_C is finite \rightarrow scrape-off layer plasma \rightarrow emission possible
- Most lines of sight pass through two SOL regions (orange example), some pass through many (blue example)

SOL-averaged ζ_{MZ}



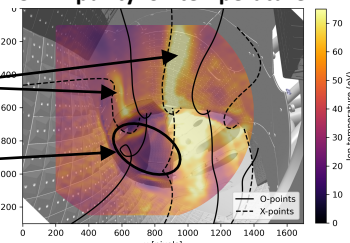
Initial scrape-off layer T_i measurements

T_i using Zeeman contrast averaged over the scrape-off layer islands

Bands of high T_i aligned with islands

Low T_i near divertor, in agreement with spectrometer measurements [D. Gradic et al, NF 61 106041 (2021)]

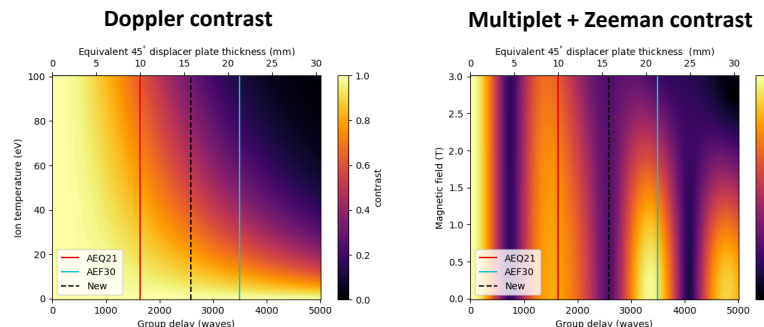
C²⁺ impurity ion temperature



C²⁺ temperature measurements are spuriously large: $T_i = 30\text{--}100$ eV, while other measurements show $T_e = 10\text{--}40$ eV \rightarrow possibly error due to Zeeman contrast variation or unaccounted for line-broadening mechanisms (bremsstrahlung, line-of-sight integration effects, spectral contamination)

Interferometer crystals optimized for measuring T_i

Birefringent crystals in two CIS instruments during OP1.2b were optimized for maximum contrast, i.e., optimized for velocity measurements, not T_i
 \rightarrow Goal: optimize crystals for C²⁺ T_i measurements using C III line at 465 nm

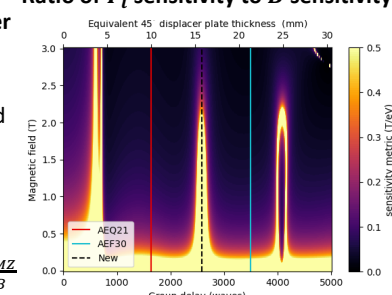


CIS sensitivity to physics parameters is determined solely by the **interferometer group delay** (proportional to crystal thickness)

Objective: maximize sensitivity to T_i and minimize sensitivity to B

- Normalized sensitivity to T_i : $S_{T_i} = \frac{1}{\zeta_D} \frac{\partial \zeta_D}{\partial T_i} = -\frac{1}{T_C}$ (depends only on group delay)
- Normalized sensitivity to B : $S_B = \frac{1}{\zeta_{MZ}} \frac{\partial \zeta_{MZ}}{\partial B}$

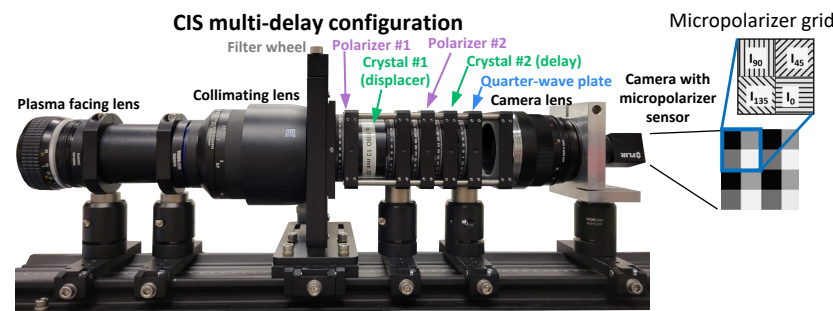
Ratio of T_i sensitivity to B sensitivity



Multi-delay CIS design

Multi-delay CIS configuration [J.S. Allcock et al, RSI 92 073506 (2021)] promises to improve T_i measurements by independently measuring B

- Standard CIS: coherence measured at one interferometer delay \rightarrow limited spectral information \rightarrow suitable for simple line shapes
- Multi-delay CIS: coherence measured at four interferometer delays simultaneously \rightarrow more spectral information \rightarrow can resolve more complex line shapes



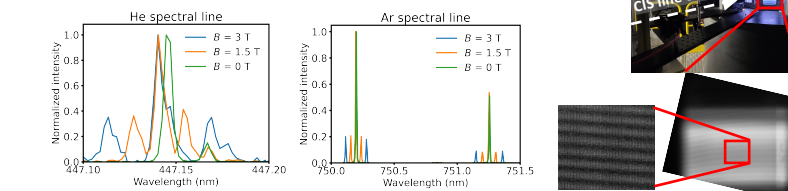
Polarizers and **crystal #1** form a linear fringe pattern, encoding coherence at delay \tilde{N}_1
Crystal #2, **quarter-wave plate**, and **polarization camera** form a pixelated fringe pattern, encoding coherence at delay \tilde{N}_2

Two fringe patterns are multiplied together, resulting in combined linear + pixelated fringe patterns encoding coherence at delays $\tilde{N}_1 + \tilde{N}_2$ and $\tilde{N}_1 - \tilde{N}_2$

Initial multi-delay CIS measurements

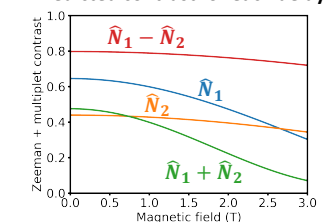
Multi-delay CIS instrument tested on the Magnetized Dusty Plasma Experiment (MDPX) [E. Thomas et al, IEEE 41 811 (2013)]

- Low-temperature (~2–4 eV), high field (>3 T) plasma source
- Excellent test bed of instrument response to Zeeman contrast with minimal Doppler broadening

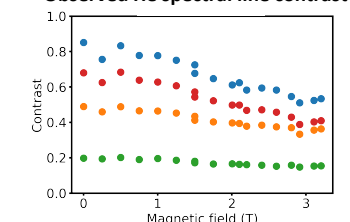


Observed CIS contrast decreases with increasing magnetic field (as predicted)

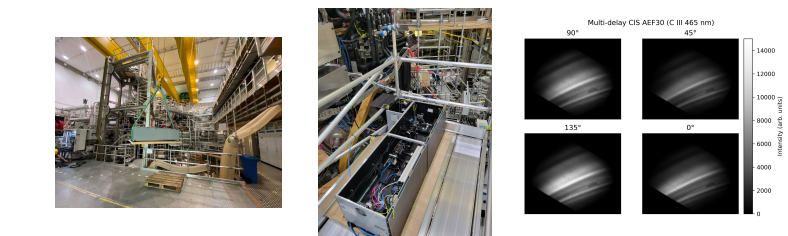
Predicted contrast for each delay



Observed He spectral line contrast



Contrast reduction (w/B-field) lower than predicted and likely due to overall low contrast levels resulting from imprecise rotational alignment of optical components



Multi-delay CIS instrument recently installed on W7-X for OP2 experimental campaign and first images were captured; commissioning in progress

Conclusions

- Analysis procedure developed to account for the effect of Zeeman splitting on CIS T_i measurements in the 3D island scrape-off layer magnetic topology of W7-X
- Initial SOL T_i measurements with flow-optimized CIS diagnostic yield high T_i bands that may be unphysical, motivating development of a new T_i -optimized instrument
- Crystals optimized for maximum ratio of T_i sensitivity to magnetic field sensitivity have been designed and procured
- Multi-delay CIS configuration developed for T_i -optimized CIS diagnostic:
 - New instrument tested on MDPX to assess effect of Zeeman splitting
 - Installed on W7-X for OP2 run campaign